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# **FCC TEST REPORT**

**Product**: Virtual Reality Headset

Trade mark : VIULUX

Model/Type reference : V1
Serial Number : N/A
Ratings : DC 5V

FCC ID : 2AGQ9-V1

Report Number : EED32H001105

Date : Nov. 30, 2015

Regulations : See below

Test Standards	Results
	PASS

### Prepared for:

Inlife-Handnet Co., Ltd 1501B, BAK Technology Building, Keyan 9th Road, Nanshan District, Shenzhen, China

Prepared by:

Centre Testing International Group Co., Ltd. Hongwei Industrial Zone, Bao'an 70 District, Shenzhen, Guangdong, China

TEL: +86-755-3368 3668 FAX: +86-755-3368 3385

Approved by:

/

Reviewed by:

pta xao

Christy Chen

Lab supervisor

Date:

Nov. 30, 2015

Check No.: 1996266637



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(Note: N/A means not applicable)		



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### 1. GENERAL INFORMATION

**Applicant:** Inlife-Handnet Co., Ltd

1501B, BAK Technology Building, Keyan 9th Road, Nanshan

District, Shenzhen, China

Manufacturer: Inlife-Handnet Co., Ltd

1501B, BAK Technology Building, Keyan 9th Road, Nanshan

District, Shenzhen, China

**Equipment Authorization:** Certification

FCC ID: 2AGQ9-V1

**Product:** Virtual Reality Headset

Trade mark: VIULUX

Model/Type reference: V1

Serial Number: N/A

Report Number: EED32H001105

Sample Received Date: Aug. 12, 2015

**Sample tested Date:** Aug. 12, 2015 to Oct. 26, 2015

The tested sample(s) and the sample information are provided by the client.

#### 2. TEST SUMMARY

The Product has been tested according to the following specifications:

Standard	Test Item	Test Item Test Method					
FCC 15.107	Conducted Emission	ANSI C63.4:2014	Yes				
FCC 15.109	Radiated Emission	ANSI C63.4:2014	Yes				

### 3. MEASUREMENT UNCERTAINTY

Where relevant, the following measurement uncertainty levels have been estimated for tests performed on the Product as specified in CISPR 16-4-2. This uncertainty represents an expanded uncertainty expressed at approximately the 95% confidence level using a coverage factor of k=2.

Test item	Value (dB)
Conducted Emission	3.4
Radiated Emission	5.3



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#### 4. PRODUCT INFORMATION AND TEST SETUP

#### 4.1. PRODUCT INFORMATION

Ratings: DC 5V

#### 4.2. TEST SETUP CONFIGURATION

See test photographs attached in Appendix 1 for the actual connections between Product and support equipment.

### 4.3. SUPPORT EQUIPMENT

No.	Device Type	Brand	Model	Series No.	Data Cable	Remark		
1.	Notebook	DELL	V3400D-326	GYQTVP1	N/A	FCC DOC		
2.	Mouse	L.Selectron	M004	02284699	Un-shielded 1.2M	FCC DOC		

#### Notes:

- 1. All the equipment/cables were placed in the worst-case configuration to maximize the emission during the test.
- 2. Grounding was established in accordance with the manufacturer's requirements and conditions for the intended use.

### 5. FACILITIES AND ACCREDITATIONS

#### 5.1. TEST FACILITY

All test facilities used to collect the test data are located at Hongwei Industrial Zone, Bao'an 70 District, Shenzhen, Guangdong, China. The site and apparatus are constructed in conformance with the requirements of ANSI C63.4, CISPR 16-1-1 and other equivalent standards.

#### 5.2. TEST EQUIPMENT LIST

**Instrumentation:** The following list contains equipments used at CTI for testing. The calibrations of the measuring instruments, including any accessories that may effect such calibration, are checked frequently to assure their accuracy. Adjustments are made and correction factors applied in accordance with instructions contained in the manual for the measuring instrument.

### **Equipment used during the tests:**

Shielding Room No. 1 - Conducted Emission Test											
Equipment	Manufacturer	Model	Serial No.	Due Date							
Receiver	R&S	ESCI	100009	06/29/2016							
LISN	R&S	ENV216	100098	06/29/2016							



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3M Semi	-anechoic Chambei	(1)- Radiated disturbance Test						
Equipment	Manufacturer	Model	Serial No.	Due Date				
3M Chamber & Accessory Equipment	ETS-LINDGREN	FACT-3	3510	07/12/2016				
Spectrum Analyzer	Agilent	E4443A	MY45300910	01/12/2016				
Receiver	R&S	ESCI	100435	06/29/2016				
TRILOG Broadband Antenna	schwarzbeck		618	06/22/2016				
Multi device Controller	ETS-LINGREN	2090	00057230	N/A				

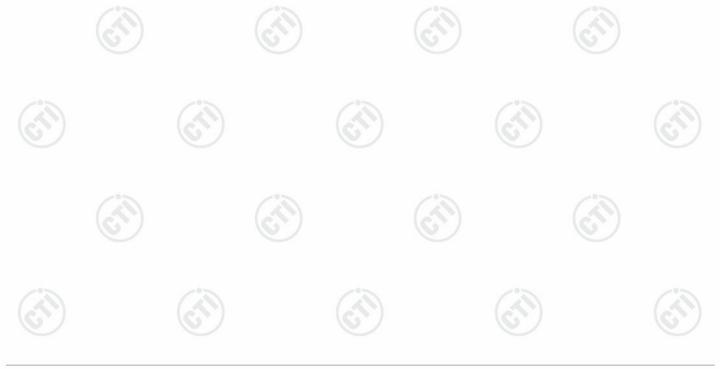
### 6. SYSTEM TEST CONFIGURATION

#### 6.1. JUSTIFICATION

The system was configured for testing in a typical fashion (as a customer would normally use it), The Product was placed on a turn table, which enabled the engineer to maximize emissions through its placement as outlined in ANSI C63.4 (2014).

For maximizing emissions, the Product was rotated through 360°, the antenna height was varied from 1 meter to 4 meters above the ground plane, and the antenna polarization was changed. The rear of unit shall be flushed with the rear of the table.

All readings are extrapolated back to the equivalent three meter reading using inverse scaling with distance. Analyzer resolution is 100 kHz or greater for frequencies below 1000 MHz. The spurious emissions more than 20 dB below the permissible value are not reported.





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### 7. CONDUCTED EMISSION TEST

#### 7.1. LIMITS

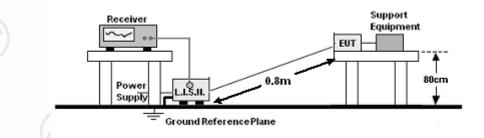
**Limits for Class B digital devices** 

Frequency range	Limits dB(μV)	
(MHz)	Quasi-peak	Average
0,15 to 0,50	66 to 56	56 to 46
0,50 to 5	56	46
5 to 30	60	50

NOTE: 1. The lower limit shall apply at the transition frequencies.

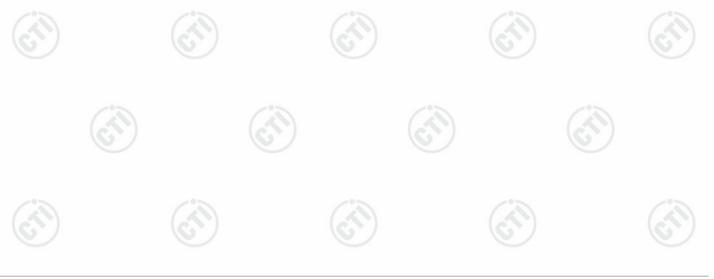
2. The limit decreases linearly with the logarithm of the frequency in the range 0.15 to 0.50 MHz.

### 7.2. BLOCK DIAGRAM OF TEST SETUP



#### 7.3. PROCEDURE OF CONDUCTED EMISSION TEST

- a. The Product was placed on a nonconductive table above the horizontal ground reference plane, and 0.4 m from the vertical ground reference plane, and connected to the main through Line Impedance Stability Network (L.I.S.N).
- b. The RBW of the receiver was set at 9 kHz in 150 kHz ~ 30MHz with Peak and AVG detector in Max Hold mode. Run the receiver's pre-scan to record the maximum disturbance generated from Product in all power lines in the full band.
- c. For each frequency whose maximum record was higher or close to limit, measure its QP and AVG values and record.





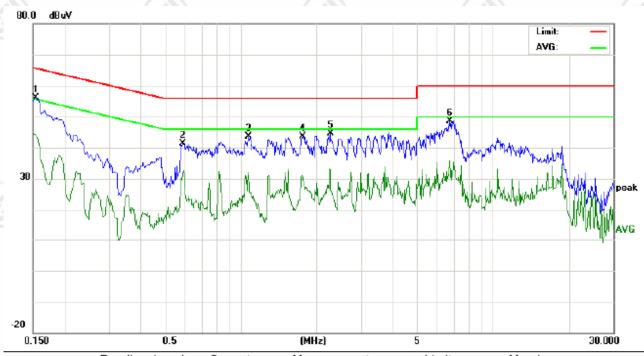
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### 7.4. GRAPHS AND DATA

Product : Virtual Reality Headset Model/Type reference : V1

Power : AC 120V/60Hz Temperature/Humidity : 23°C/58%

Mode : Normal Phase : L



	No.	Freq.		ding_Le dBuV)	vel	Correct Factor				Limit Margii (dBuV) (dB)		_			
í		MHz	Peak	QP	AVG	dB	peak	QP	AVG	QP	AVG	QP	AVG	P/F	Comment
	1	0.1499	45.22	41.30	34.81	9.90	55.12	51.20	44.71	66.00	56.00	-14.80	-11.29	Р	
	2	0.5899	31.42	27.80	21.44	9.90	41.32	37.70	31.34	56.00	46.00	-18.30	-14.66	Р	
	3	1.0740	33.65	30.04	20.85	9.90	43.55	39.94	30.75	56.00	46.00	-16.06	-15.25	Р	
	4	1.7620	33.61	29.50	20.79	9.90	43.51	39.40	30.69	56.00	46.00	-16.60	-15.31	Р	
	5	2.2620	34.66	31.27	22.64	9.90	44.56	41.17	32.54	56.00	46.00	-14.83	-13.46	Р	
	6	6.7419	38.80	34.00	25.88	9.90	48.70	43.90	35.78	60.00	50.00	-16.10	-14.22	Р	



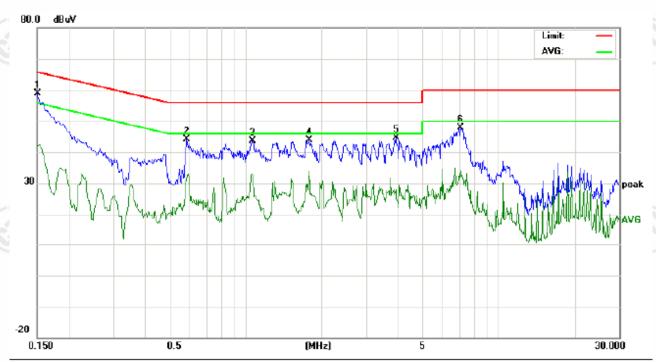




Product : Virtual Reality Headset Model/Type reference : V1

Power : AC 120V/60Hz Temperature/Humidity :  $23^{\circ}$ C/58%

Mode : Normal Phase : N



No.	Freq.		ding_Le dBuV)	vel	Correct Factor	Measurement (dBuV)		Limit (dBuV)			Margin (dB)			
	MHz	Peak	QP	AVG	dB	peak	QP	AVG	QP	AVG	QP	AVG	P/F	Comment
1	0.1500	48.97	44.00	32.30	9.90	58.87	53.90	42.20	65.99	55.99	-12.09	-13.79	Р	
2	0.5860	34.30	30.10	20.96	9.90	44.20	40.00	30.86	56.00	46.00	-16.00	-15.14	Р	
3	1.0660	33.75	30.14	22.75	9.90	43.65	40.04	32.65	56.00	46.00	-15.96	-13.35	Р	
4	1.7860	34.03	31.60	23.96	9.90	43.93	41.50	33.86	56.00	46.00	-14.50	-12.14	Р	
5	3.9260	34.71	30.80	17.91	9.90	44.61	40.70	27.81	56.00	46.00	-15.30	-18.19	Р	
6	7.0860	37.88	33.57	24.45	9.90	47.78	43.47	34.35	60.00	50.00	-16.53	-15.65	Р	





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### 8. RADIATED EMISSION TEST

#### 8.1. LIMITS

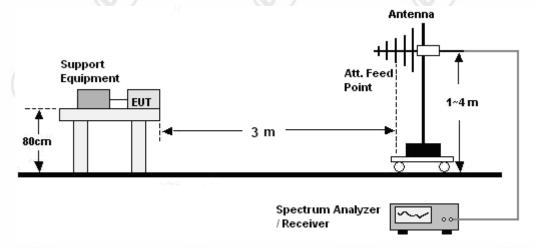
Limits for Class B digital devices

Frequency (MHz)	limits at 3m
	dB(μV/m)
30-88	40.0
88-216	43.5
216-960	46.0
Above 960	54.0

**NOTE:** 1. The lower limit shall apply at the transition frequency.

- 2. The limits shown above are based on measuring equipment employing a CISPR quasi-peak detector function for frequencies below or equal to 1000MHz.
- The limits shown above are based on measuring equipment employing an average detector function for frequencies above 1000MHz.

### 8.2. BLOCK DIAGRAM OF TEST SETUP



#### 8.3. PROCEDURE OF RADIATED EMISSION TEST

- a. The Product was placed on the non-conductive turntable 0.8m above the ground at a chamber.
- b. Set the spectrum analyzer/receiver in Peak detector, Max Hold mode, and 120 kHz RBW. Record the maximum field strength of all the pre-scan process in the full band when the antenna is varied between 1~4 m in both horizontal and vertical, and the turntable is rotated from 0 to 360 degrees.
- c. For each frequency whose maximum record was higher or close to limit, measure its QP value: vary the antenna's height and rotate the turntable from 0 to 360 degrees to find the height and degree where Product radiated the maximum emission, then set the test frequency analyzer/receiver to QP Detector and specified bandwidth with Maximum Hold Mode, and record the maximum value.



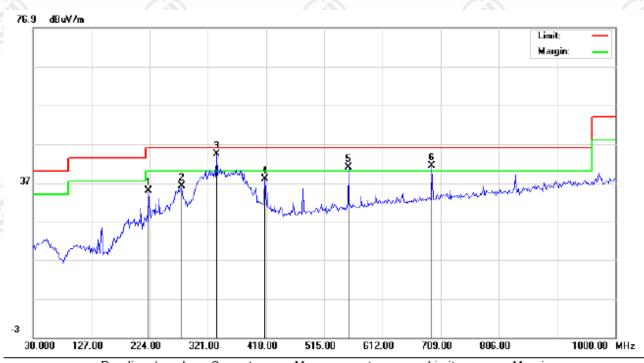


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### 8.4. GRAPHS AND DATA

Product: Virtual Reality Headset Model/Type reference: V

Power : DC 5V Temperature/Humidity : 24 ℃/50% Mode : Normal Polarization : Horizontal



	No.	Freq.		ding_Le dBuV)	vel	Correct Factor		Measurement (dBuV/m)		Limit (dBuV/m)		Margin (dB)			
		MHz	Peak	QP	AVG	dB	peak	QP	AVG	QP	AVG	QP	AVG	P/F	Comment
	1	222.3833	20.92	19.40		14.04	34.96	33.44		46.00		-12.56		Р	
•	2	277.3500	20.53	17.20		15.63	36.16	32.83		46.00		-13.17		Р	
	3	335.5500	27.09	26.00		17.32	44.41	43.32		46.00		-2.68		Р	
	4	416.3833	18.81	18.24		19.23	38.04	37.47		46.00		-8.53		Р	
	5	555.4167	18.84	18.10		22.22	41.06	40.32		46.00		-5.68		Р	
•	6	694.4500	17.06	16.35		24.29	41.35	40.64		46.00		-5.36		Р	

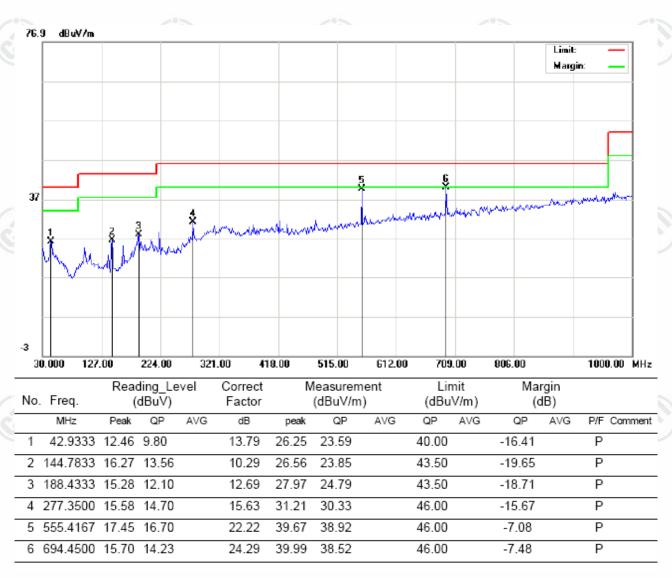




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Product: Virtual Reality Headset Model/Type reference: V1

Power : DC 5V Temperature/Humidity : 24℃/50% Mode : Normal Polarization : Vertical



#### Remark:

The highest frequency of the internal sources of the EUT is less than 108 MHz, so the measurement shall only be made up to 1 GHz.



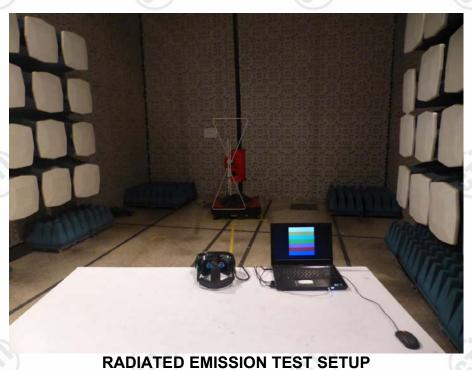


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## **APPENDIX 1 PHOTOGRAPHS OF TEST SETUP**



**CONDUCTED EMISSION TEST SETUP** 















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## **APPENDIX 2 PHOTOGRAPHS OF PRODUCT**



View of Product-1

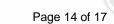


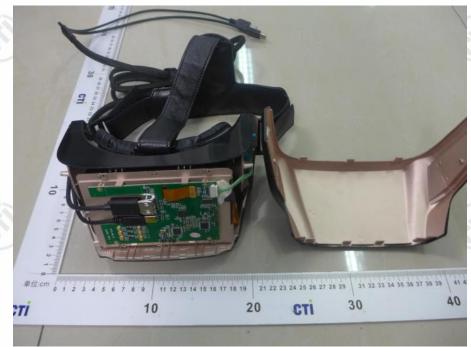
View of Product-2











View of Product-3



View of Product-4











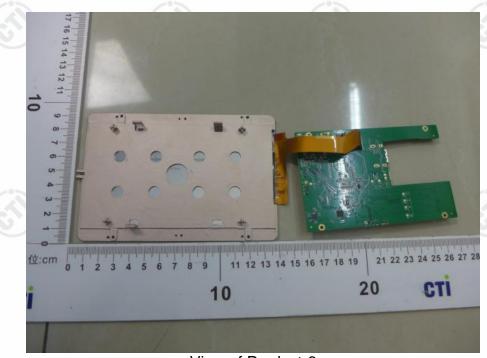








View of Product-5



View of Product-6





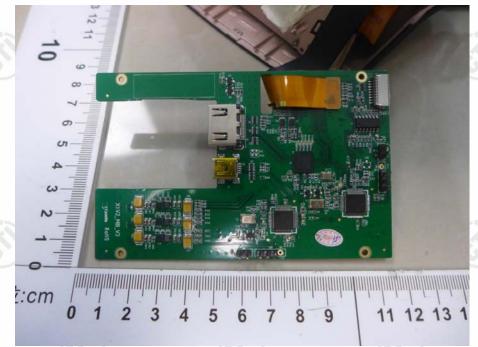




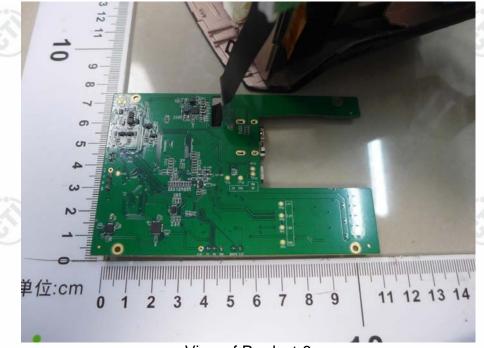








View of Product-7



View of Product-8







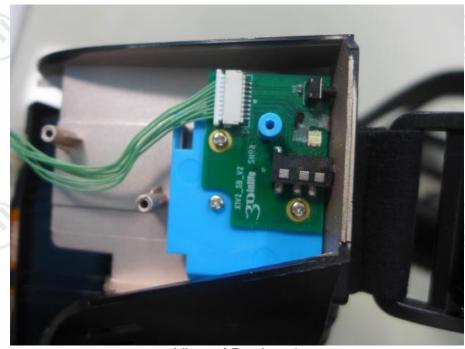












View of Product-9



### End of Report \*\*\*

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